

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/085,919	MAYER ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Cynthia Britt	2133	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,006,347	12-1999	Churchill et al.	714/724
	B	US-5,777,489	07-1998	Barbier et al.	326/40
	C	US-5,642,363	06-1997	Smith, Gregory James	714/729
	D	US-6,094,729	07-2000	Mann, Daniel P.	714/25
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	S. Narayanan et al., "Reconfigurable scan chains: A novel approach to reduce test application time", Proceedings of ICCAD, p 710-715, Sep. 1993.
	V	Narayanan, S. and Breuer, M.A.; Reconfiguration techniques for a single scan chain; IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol.: 14 Issue: 6, Jun. 1995, Page(s): 750-765.
	W	IBM Technical Disclosure Bulletin (TDB-ACC-NO) NA9003105 "Programmable Microcoded Self-Test Apparatus for Processor Cache Memory" March 1990, US, Vol 32, Issue 10A, PAGES105-107, publication date March 1, 1990.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.